Custom specification OXO214-1000-007

Optimised performance 10.00MHz DIL OCXO

temperature tolerance: ±0.2ppm(-40 +70)°C
phase noise: -150dBc/Hz, f_0 +100KHz
supply +3.3V d.c.
quiescent current: 250mA max.
RoHS compliant

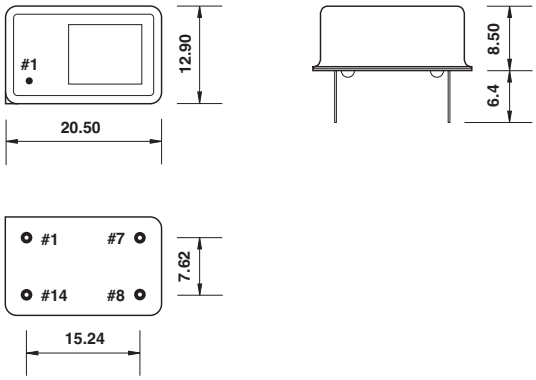
Custom specification:

frequency:	*10.000MHz*
temperature tolerance:	*±0.2ppm(-40 +70)°C*
output:	*CMOS 15pF, 45% ~ 55%*
	<2ns max. rise and fall
supply voltage:	*+3.3Vd.c.*

Generic specification:

stability:	
against supply voltage change	*±0.02ppm max. for V_{cc} ±5%*
against load change	*±0.02ppm max. for load ±10%*
ageing short term	*±0.005ppm max. per day after 30 days continuous operation*
ageing long term	*±1.0ppm max. first year after 30 days continuous operation*
voltage trim V_t	*±10ppm min. typical linearity ±5%*
trim input impedance	*100KΩ min.*
power supplies:	
supply voltage V_{cc}	*+3.3Vd.c.*
start up current	*500mA max. at -40°C*
quiescent current	*250mA max. at +70°C*
warm up time	*5 minutes max. to within 0.1ppm of nominal*
insulation resistance	*500MegΩ min., 100Vd.c.*
phase noise:	*-90dBc/Hz, f_o+10Hz*
	-120dBc/Hz, f_o+100Hz
	-135dBc/Hz, f_o+1kHz
	-140dBc/Hz, f_o+10kHz
	-150dBc/Hz, f_o+100kHz
temperature:	
operating range	*(-40 +70)°C*
storage range	*(-40 +125)°C*

Dimensions(mm):

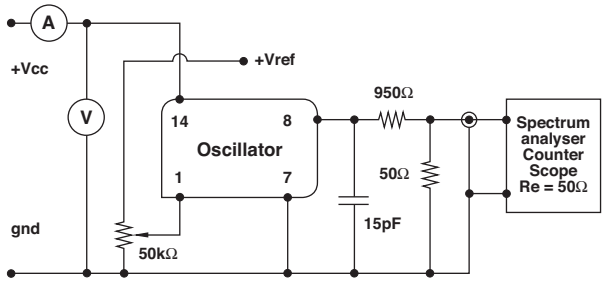


Pins viewed from bottom
pin diameter 0.45mm

Pin connections:

 # 1 trim
 # 7 ground/case
 # 8 output
 # 14 +V_{cc}

Test circuit, CMOS load:



test circuit includes a 20:1 step down into a matched 50Ω load

Environmental conditions:

MIL standard 202F	*method 213, condition J*
MIL standard 202F	*method 107, condition A*
MIL standard 202F	*method 204, condition B*
solderability	*5 seconds max. at +230°C*
	3 seconds max. at +350°C

Telephone: +1 905 623 4101, Fax: +1 905 623 3886
e-mail: sales@laptech.com website: www.laptech.com